

BACK-END

MOS-FET

IGBT

DIODE

# SWITCHING TIME TEST SYSTEM スイッチングタイムテストシステム

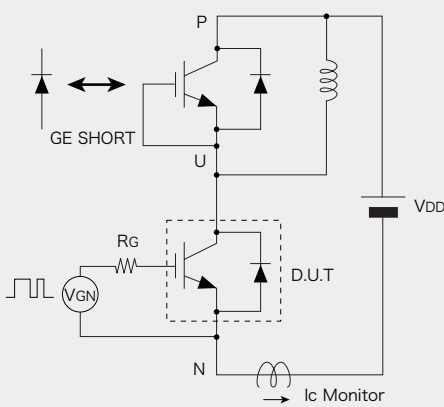
## SWQRL1020Z

1000V  
200A

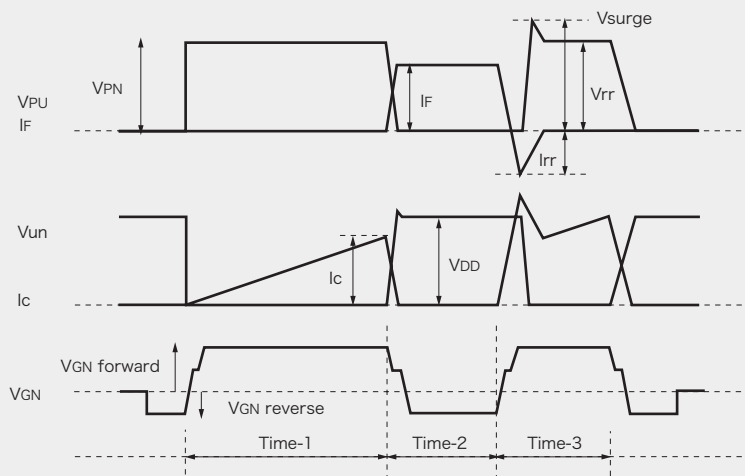
- SWQRL1020Z has been designed to be as compact as possible, with sufficient measurement space for workability. The construction corresponds to the measurement of the measuring section mainly 3-terminal products.
- SWQRL1020Z は作業性を重視した測定スペースを十分に確保し、できる限りコンパクトにまとめた装置です。測定部は主に 3 端子品の測定に対応した構造となっています。



Fundamental Test Circuit (L-LOAD Switching)



Measurement Waveform (L-LOAD Switching)



## MODEL

SWQRL1020Z

## TEST ITEMS

R-LOAD/L-LOAD SWITCHING

Ic(I<sub>D</sub>), td(on), tr, td(off), tf, e(on), e(off)

di/dt

Irr, trr, Qrr, dif/dt, dir/dt, Vdsurge

QG

Qgs, Qgd, Qg, Vth

## SETTING RANGE

MEASURABLE DEVICE

MOS-FET, IGBT, DIODE

MEASUREMENT RANGE

000.0 $\mu$ s~9999 $\mu$ s

VDD

20V~1000V 1V STEP

Id(Limit)

1.0A~200.0A 0.1A STEP

VGF/VGR

 $\pm$ 00.00V~ $\pm$ 30.00V 0.01V STEP

IG

 $\pm$ 0.1mA~ $\pm$ 10.0mA 0.1mA STEP

Time-1

000.0 $\mu$ s~999.9 $\mu$ s 0.1 $\mu$ s STEP

Time-2

000.0 $\mu$ s~999.9 $\mu$ s 0.1 $\mu$ s STEP

Time-3

00.0 $\mu$ s~99.9 $\mu$ s 0.1 $\mu$ s STEP

Time-4

000 $\mu$ s~9999 $\mu$ s 1 $\mu$ s STEP

RgF/RgR

0.0 $\Omega$ ~99.9 $\Omega$  0.1 $\Omega$  STEP

## BINNING

OPEN/SHORT CHECK

VF1 &gt; 5V...OPEN

VKA &lt; 8V...SHORT

BIN INDICATION

ERROR, PASS, LIMIT-FAIL, OPEN, SHORT

## DIMENSIONS &amp; WEIGHT

MAIN UNIT

1070(W) $\times$ 1050(D) $\times$ 1860(H)...400kg